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	Application No.	Applicant(s)	
Notice of Allowability	10/077,036	PARKER ET AL.	·
	Examiner	Art Unit	
	Phillip A. Johnston	2881	
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.			
1. X This communication is responsive to Appeal Brief filed 6-17-2005.			
2. ⊠ The allowed claim(s) is/are <u>70-109,111-127 and 129-147</u> .			
3. 🔀 The drawings filed on <u>15 February 2002</u> are accepted by the Examiner.			
4. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some* c) None of the: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No. 3. Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)). * Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application. THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 5. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient. 6. CORRECTED DRAWINGS (as "replacement sheets") must be submitted. (a) including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d). 7. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.			
Attachment(s) 1. ☐ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/06 Paper No./Mail Date 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	5. ☐ Notice of Informal P 6. ☐ Interview Summary Paper No./Mail Dat 8), 7. ☐ Examiner's Amendr 8. ☑ Examiner's Stateme 9. ☐ Other	(PTO-413), te ment/Comment	

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Examiner's statement of reasons for allowance

The following is an examiner's statement of reasons for allowance:

- 1. Claims 70,89,105,129,145, and 147 are allowed because prior art fails to show a spectral processing method for compensating a plurality of sequential spectra and profiles derived therefrom for effects of drift of data along an independent variable axis, comprising: transforming a plurality of sequential spectra obtained from a spectrometer to provide an array of row vectors compensated for effects of drift of data along an independent variable axis, wherein the array of row vectors compensated for effects of drift of data along the independent variable axis constitutes a drift-compensated array; performing a principal-factor determination on the drift-compensated array to provide a set of principal factors compensated for effects of drift of data along the independent variable axis; and generating, from a profile trajectory of the row vectors compensated for effects of drift of data along the independent variable axis lying within a space of principal factors compensated for effects of drift of data along the independent variable axis, scaled target-factor profiles compensated for effects of drift of data along the independent variable axis.
- 2. Claims 71-88,90-104,106-109,11-127,130-144, and 146 are allowed by virtue of their dependency upon allowed claims 70,89,105,129,145, and 147.
- 3. The examiner agrees with Applicant's arguments presented in the appeal brief filed 6-17-2005, particularly that, Haaland's prediction curve generated from matrixed spectral shape data is not equivalent to applicants generated profile trajectory.

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Statement of Reasons for Allowance."

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Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on

Conclusion

the application or proceeding is assigned is 703 872 9306.

4. Any inquiry concerning this communication or earlier communications should be directed to Phillip Johnston whose telephone number is (571) 272-2475. The examiner can normally be reached on Monday-Friday from 7:30 am to 4:00 pm. If attempts to reach the examiner by telephone are unsuccessful, the examiners supervisor John Lee can be reached at (571) 272-2477. The fax phone number for the organization where

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ΡJ

August 29, 2005

JOHN R. LEE

SUPERVISORY PATENT EXAMINER